**Power Up**

1. If system is not already on, turn on the Dektak 8 by flipping the power switch located on the rear panel of the EBox connected to the profiler cover.

![Power switch located on the rear panel of the E-Box](image)

2. Turn the monitor on by depressing the power button located on the front of the monitor in the lower-middle.
3. Turn the computer on by pressing the power switch located on the front of the computer.
4. Double click on the Dektak32 icon on the desktop or `SELECT START>ALL PROGRAMS>DEKTAK32>Dektak32` from the Windows toolbar.
5. The Dektak 8 sample stage will initialize and the Start Screen Window will display.
6. Go to **FILE/NEW** to start a new scan.

**Sample Loading**

1. To load sample, move stage to the load/unload position by clicking the unload command button ![Unload button](image) in the stage control panel on the right side of the screen.
2. Open guard panel door.
3. Load wafer onto stage, centering wafer to the vacuum stage, then turn on the vacuum via toggle switch on left of Dektak 8 chassis.

4. Once wafer is mounted, click "YES" in the Load Sample dialog box (Fig. 2) to return stage to home position. The stage has finalized homing protocol when the output text in the lower left hand corner displays "READY".

![Stage return dialog box](image)

5. Close guard panel door.

6. Press the "TOWER DOWN TO NULL POSITION STYLUS UP" icon.
   a. This traverses stylus to substrate surface, then releases stylus for additional positioning (without damaging stylus)
   b. **NOTE:** Be aware of sample position with respect to stylus tip before lowering

**Standard Single Scan Sequence**

1. Click on the scan routines window icon.
   a. Adjust scan parameters by clicking any link (Fig. 3) to open scan parameters dialog box (Fig. 4).
b. Scan parameters:

**ID** - Filename desired

**Stylus Type** - 12.5 μm radius tip (for note purposes only, does not affect scan)

**Scan Duration** - Time required completing scan from beginning to end
- The longer the scan duration, the more data points recorded and more time required for scan.

**Scan Type** - Standard Scan

**Stylus Force** - Force applied to substrate by stylus input range (0.7 to 15 mg)
- For soft materials (i.e. photoresist, polymers, soft metals, gold) use low force such as 1 to 2 mg
- For hard materials (i.e. chrome, nickel, silicon, glass) use higher force such as 10 to 15 mg

**Measurement Range** - Four step ranges, 1 mm, 2620 kA (286.6 um), 655 kA (65.5 um), 65 kA (6.5 um)

**Profile** - Hills, Valleys, or Hills & Valleys, depending on feature geometry

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c. Click OK.

2. Return to the Sample Positioning Window by clicking the Sample Positioning Window icon.

3. Move to desired start position on sample by either:
   
   a. Left clicking in view window and moving the stage with the mouse
b. Using the positioning arrows (Fig 5) in the stage control panel.

![Fig 5. Positioning arrows](image)

4. Go to **EDIT/DEFINE SCAN LOCATION**, to input your start scan position  
   a. Click **ENTER**  
   b. Close.

5. Go to **EDIT/DEFINE SCAN LENGTH**  
   a. Using the mouse move to the desired endpoint of scan, keep in mind that the motion of this move is unidirectional (i.e. left/right motion in the viewing window)  
   b. Left click mouse to define endpoint  
   c. Click **ENTER**  
   d. Close.

6. Run the programmed Standard Scan.

**3D Map Scan Sequence**

1. Click on scan routines window icon.
   a. Adjust scan parameters by clicking any link (Fig. 6) to open scan parameters dialog box (Fig.7)
b. Scan parameters:

<table>
<thead>
<tr>
<th>ID</th>
<th>Filename</th>
</tr>
</thead>
<tbody>
<tr>
<td></td>
<td></td>
</tr>
</tbody>
</table>

**Stylus Type** - 12.5 um radius tip (for note purposes only, does not affect scan)

**Scan Duration** - Time required completing scan from beginning to end

**Scan Type** - Map Scan

**Stylus Force** - Force applied to substrate by stylus input range (0.7 to 15 mg)
- For soft materials (i.e. photoresist, polymers, soft metals, gold) use low force such as 1 to 2 mg.
- For hard materials (i.e. chrome, nickel, silicon, glass) use higher force such as 10 to 15 mg.

**Measurement Range** - Four step ranges, 1 mm, 2620 kA (286.6 um), 655 kA (65.5 um), 65 kA (6.5 um)

**Profile** - Hills, Valleys, or Hills & Valleys, depending on feature geometry

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c. Click **OK**

2. Return to the Sample Positioning Window by clicking the Sample Positioning Window icon.

![Scan Parameters Dialog Box]

3. Move to desired start position on sample by either:
   
   a. Left clicking in view window and moving the stage with the mouse.
   
   b. Using the positioning arrows (Fig 8) in the stage control panel.
4. Go to **EDIT/DEFINE MAP AREA**
   
a. Move to the desired X direction endpoint (Left/Right unidirectional motion in view window).
   
b. Left click in view window to define point.
   
c. Move to the desired Y direction endpoint (Up/Down unidirectional motion in view window).
   
d. Left click in view window to define point.
   
e. Map Parameters dialog opens (Fig 9).

5. Input:
   
a. Lateral parameters - # profiles, this depends on desired resolution and feature size (min. resolution = 1 um).
   
b. Choose desired image resolution.
   
c. Check Re-Null Tower under Additional Parameters.
6. Run the programmed Map Scan.

7. To analyze map scan:
   a. Minimize Dektak32 window.
   b. Open Vision software by double clicking on icon on desktop.
   c. Go to FILE/OPEN stored dataset

Sample Unloading

1. To unload sample, move stage to the load/unload position by clicking the unload command button in the stage control panel on the right side of the screen.

2. Open guard panel door.

3. Turn the vacuum off via toggle switch on left of Dektak 8 chassis and remove sample.

4. Close guard panel door.

5. Once sample is removed, click “YES” in the Load Sample dialog box to return stage to home position. The stage has finalized homing protocol when the output text in the lower left hand corner displays “READY”.